Search Notes



Application/Control N	łc
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Applicant(s)/Patent Under Reexamination

LOW, YEE CHEOK

Examiner

Art Unit

HENOK G HEYI

2627

	SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
Searched EAST. Some of the subclasses searched are 369/30.36, 44.27	02/20/2009	HH	
and 53.28 (text search only - please see search history printout).			

INTERFERENCE SEARCH Class Subclass Date Examiner

/HENOK G HEYI/ Examiner.Art Unit 2627	

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